

INTERNATIONAL ATOMIC ENERGY AGENCY
UNITED NATIONS EDUCATIONAL, SCIENTIFIC AND CULTURAL ORGANIZATION
INTERNATIONAL CENTRE FOR THEORETICAL PHYSICS
I.C.T.P., P.O. BOX 586, 34100 TRIESTE, ITALY, CABLE CENTRATOM TRIESTE



SMR/455 - 27

**EXPERIMENTAL WORKSHOP ON HIGH TEMPERATURE
SUPERCONDUCTORS & RELATED MATERIALS
(BASIC ACTIVITIES)**

12 - 30 MARCH 1990

**HREM OF
SUPERCONDUCTING CERAMICS**

**GUSTAAF VAN TENDELOO
H.W. ZANDBERGEN*
J. VAN LANDUYT
S. AMELINCKX**

University of Antwerp
(R.U.C.A.)
Groenenborgerlaan 171
Antwerp B-2020
Belgium

* University of Leiden
Center for HREM
Delft

These are preliminary lecture notes, intended only for distribution to participants.

HREM of Superconducting Ceramics

**G. Van Tendeloo
H.W. Zandbergen *
J. Van Landuyt
S. Amelinckx**

University of Antwerp (RUCA)

*** University of Leiden
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IMAGE FORMATION

Electron Microscopy of High Tc Superconductors

Electron Microscopy ??

- a) "big lens"
- b) beam - specimen interaction

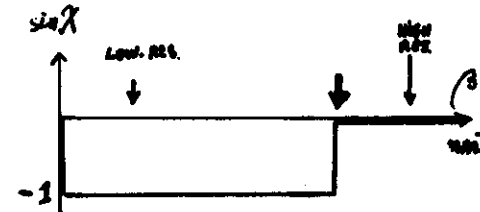
High Tc Superconductors ??

- specific problems

1. YBa₂Cu₃O_{7-δ}
2. YBa₂Cu₃O₈
3. BSCCO, TBCCO
4. PSYCCO
5. Bi(Ba-K)O₃

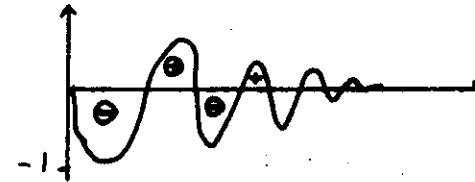
$$\psi(x,y) = \mathcal{F} \left[Q(u,v) \underbrace{e^{-i\chi(u,v)}} \right]$$

"THE WAY REALITY
IS DISTORTED BY THE
MICROSCOPE ?"



"IDEAL MICROSCOPE"

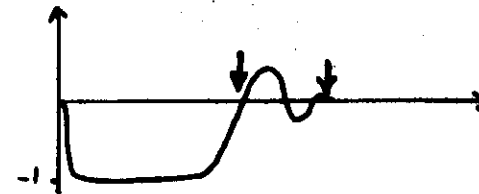
$$I(x,y) = 1 - \varphi(x,y)$$



"REAL MICROSCOPE - GENERAL"

$$I(x,y) = \text{VERY COMPLEX...}$$

(FUNCTION OF $\Delta f, \text{EM}, \dots$)



"REAL MICROSCOPE - SCHERER"

$$\sin \chi \approx 1$$

$$I(x,y) \approx 1 - \text{cte } \varphi(x,y)$$

① NO DETAILED ATOM POSITIONS

NO INTERATOMIC DISTANCES

ONLY PROJECTED INFORMATION

⊕ • FAST

• NO "SINGLE CRYSTALS" REQUIRED

• REAL SPACE ⊕ RECIPROCAL SPACE INFO

• DETECTION OF IMPERFECTIONS

(on atomic scale)

• SMALL AMOUNTS SECONDARY PHASES

(< 10 nm!)

→ structure (unit cell)

→ ≈ composition

→ relationship to matrix

E.M. of $\text{YBa}_2\text{Cu}_3\text{O}_{9-\delta}$

- ϕ 2.3 - 3 mm

- thickness < 200 nm EM

< 20 nm HREM

How?

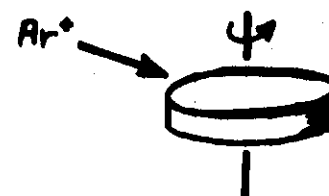
① crushed material

small flakes on a grid

⊕ good for HREM

⊖ no | inter-domain | relationship
| inter-grain |

② ion beam thinned material



⊕ inter grain, domain size, habit plane

⊖ ! artifacts (e.g. amorphisation)

ELECTRON MICROSCOPY

⊖ NO DETAILED ATOM POSITIONS

NO INTERATOMIC DISTANCES

ONLY PROJECTED INFORMATION

⊕ • FAST

• NO 'SINGLE CRYSTALS' REQUIRED

• REAL SPACE @ RECIPROCAL SPACE INFO

• DETECTION OF IMPERFECTIONS

(on sharp spots)

• SMALL AMOUNTS OF SAMPLE REQUIRED

($< 10 \text{ nm}^3$)

→ structure (unit cell)

→ composition

→ relationship to matrix

Y-Ba-Cu-O

A. $\text{YBa}_2\text{Cu}_3\text{O}_{7-8}$

• structure of the (110) twins

• the influence of oxygen

$\text{O}1 \rightarrow 2\text{a}_0 \rightarrow (\text{na}_0) \rightarrow 2\sqrt{2} \times 2\sqrt{2} \rightarrow \text{cubic}$

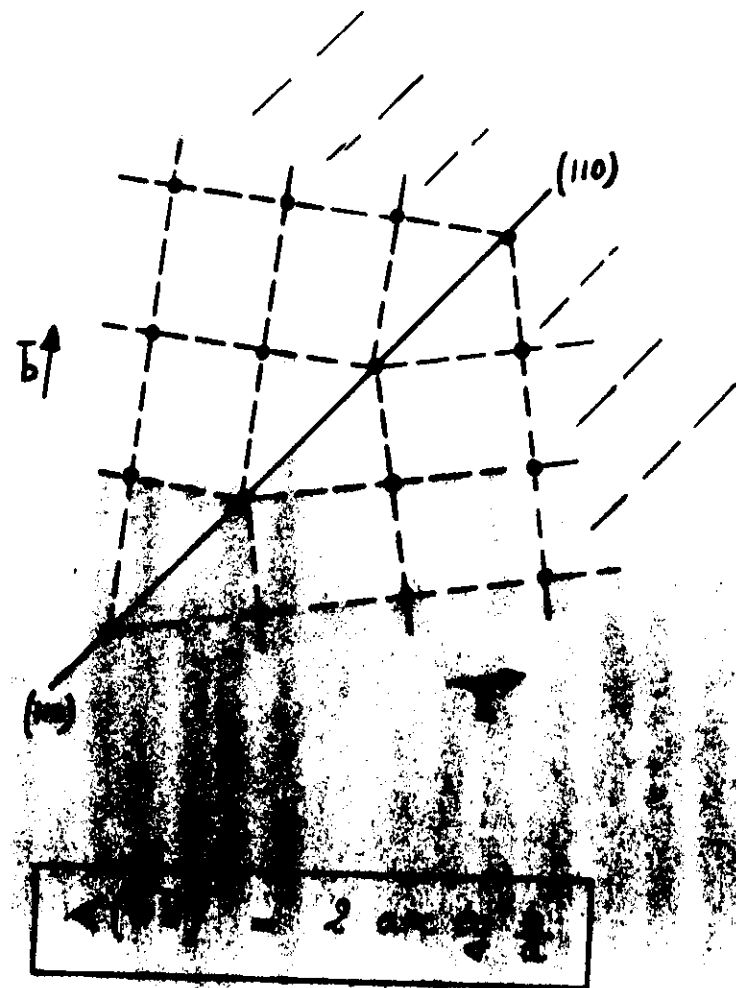
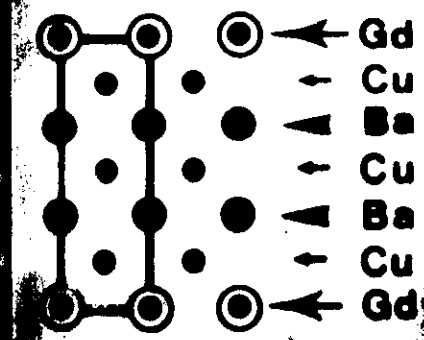
• the 60K plateau at $\text{O}_{6.5}-\text{O}_{6.6}$ (K.U. Leuven)

(Argonne Nat. Lab.)

• the $2\sqrt{2} \times 2\sqrt{2}$ structure

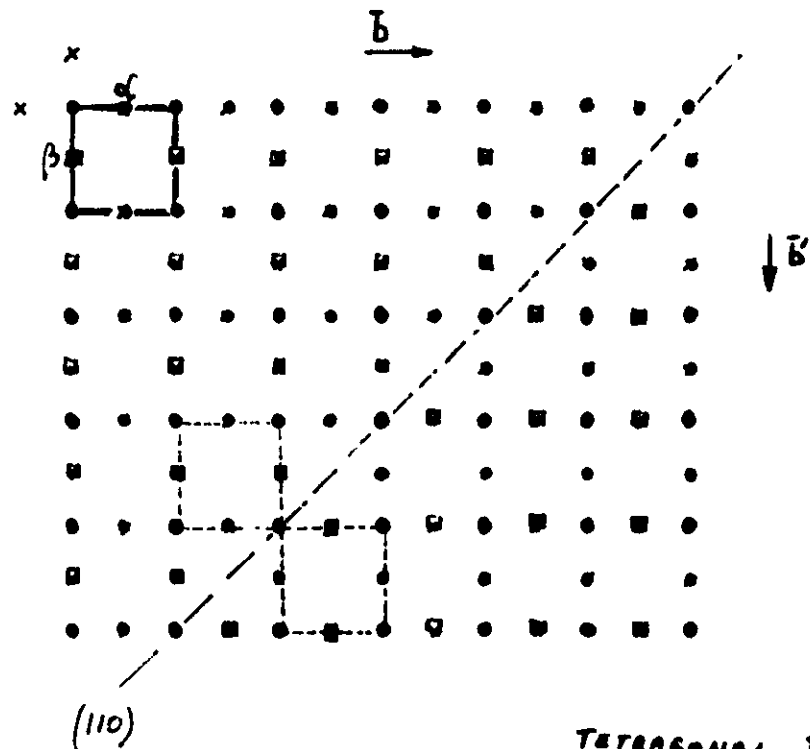
• heavy ion irradiation (Orsay)

• Fe - doped 1-2-3 (ULB Bruxelles)



Cu-O plane configuration

in $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$

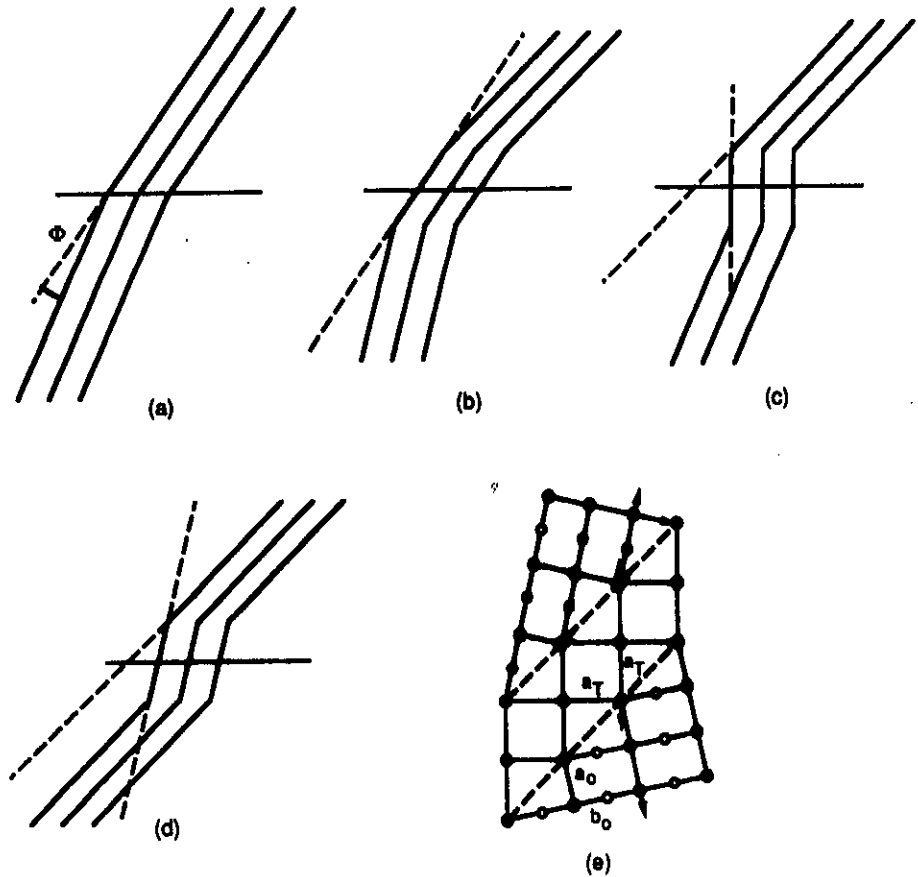


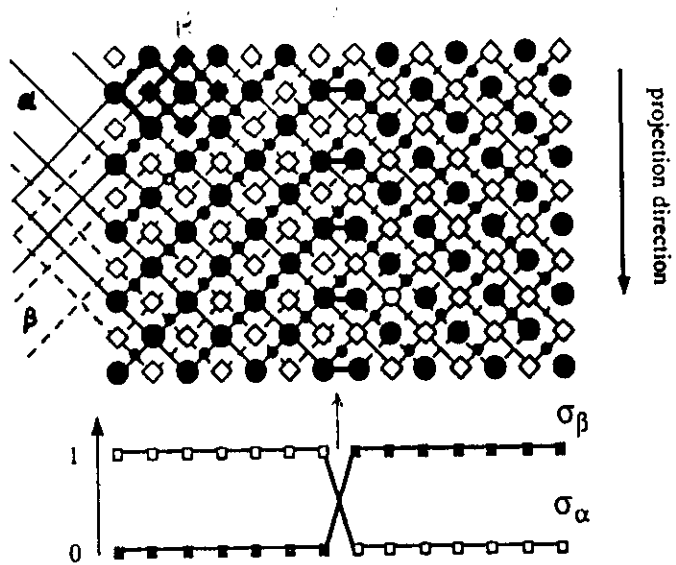
TETRAGONAL PHASE
ORTHORHOMBIC PHASE

$$a = 0.382 \text{ nm}$$

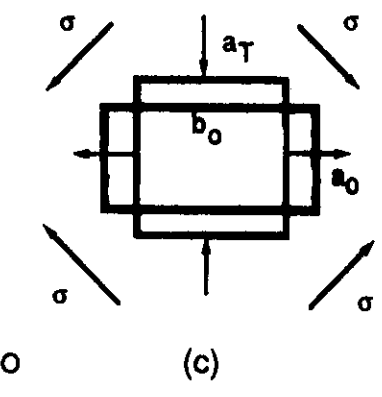
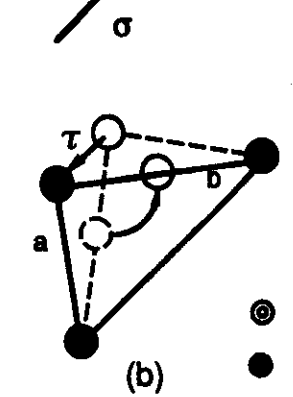
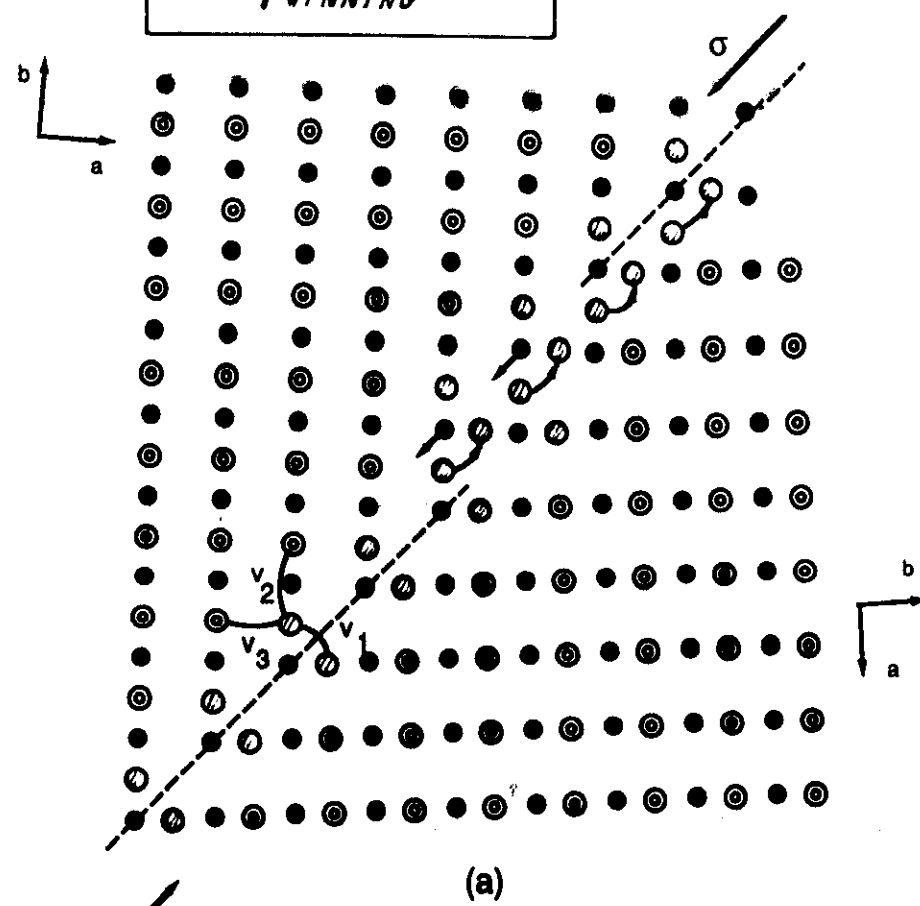
$$b = 0.389 \text{ nm}$$

$$c = 0.167 \text{ nm}$$





SYNCHRONOUS TWINNING



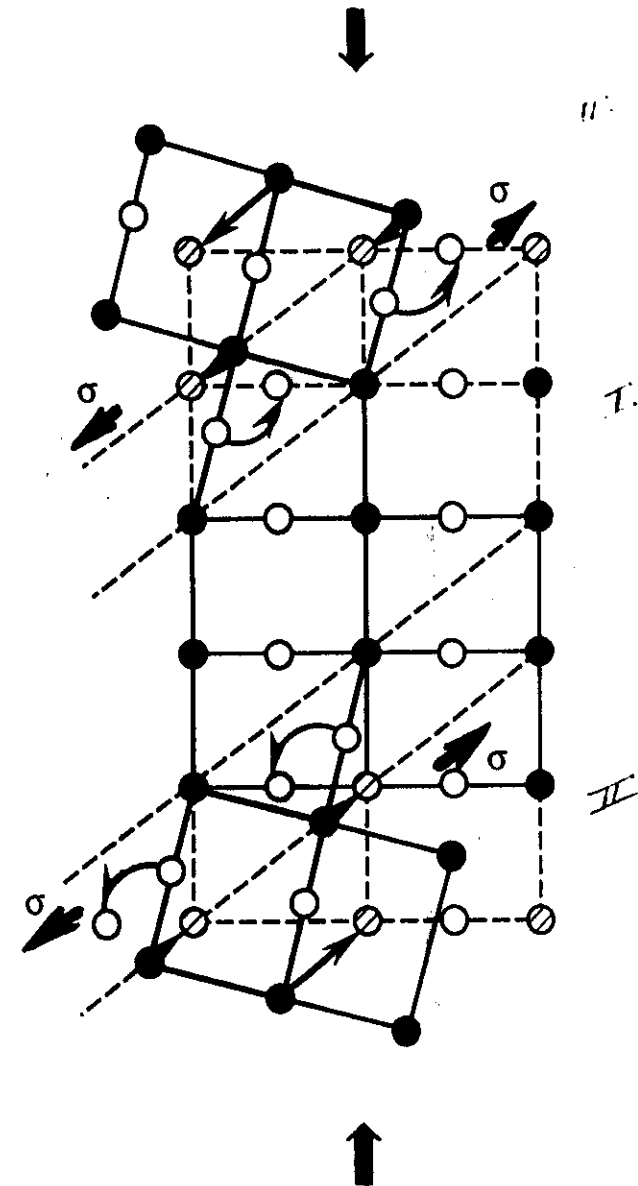
- $\odot$ Fully occupied O
- $\bullet$ Partially occupied O
- $\cdot$ Cu

DETWINNING UNDER STRESS

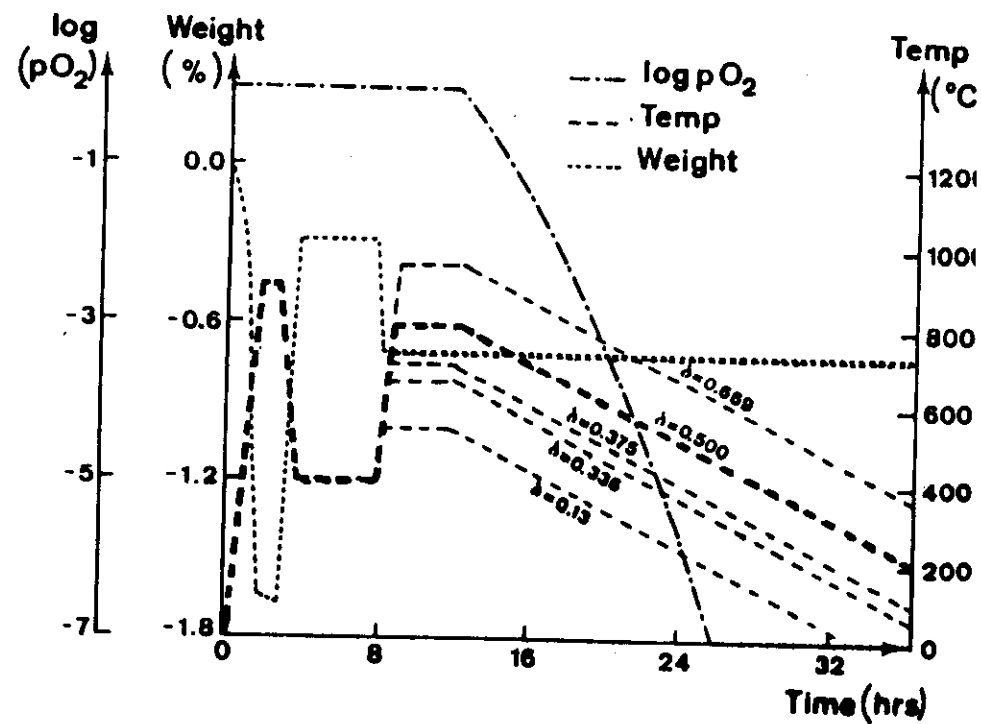
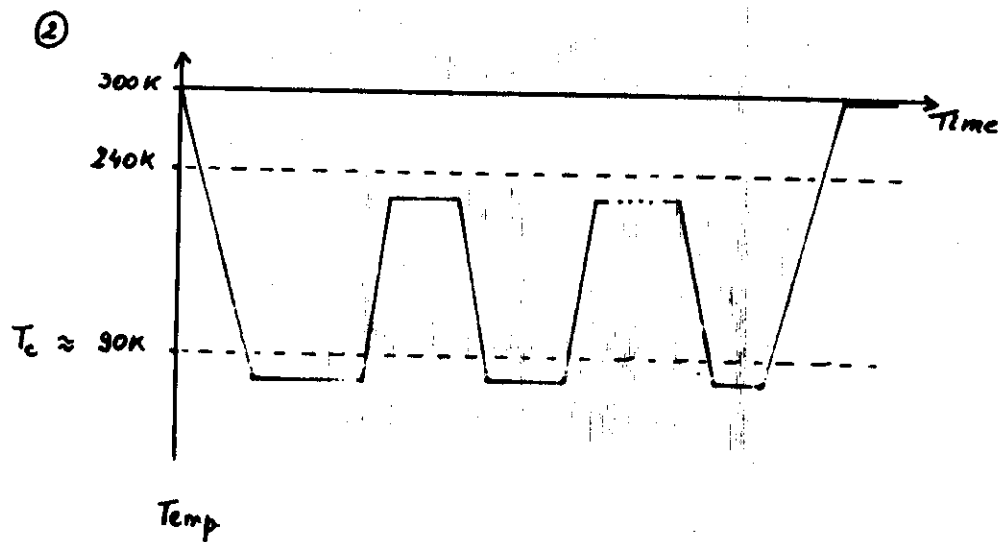
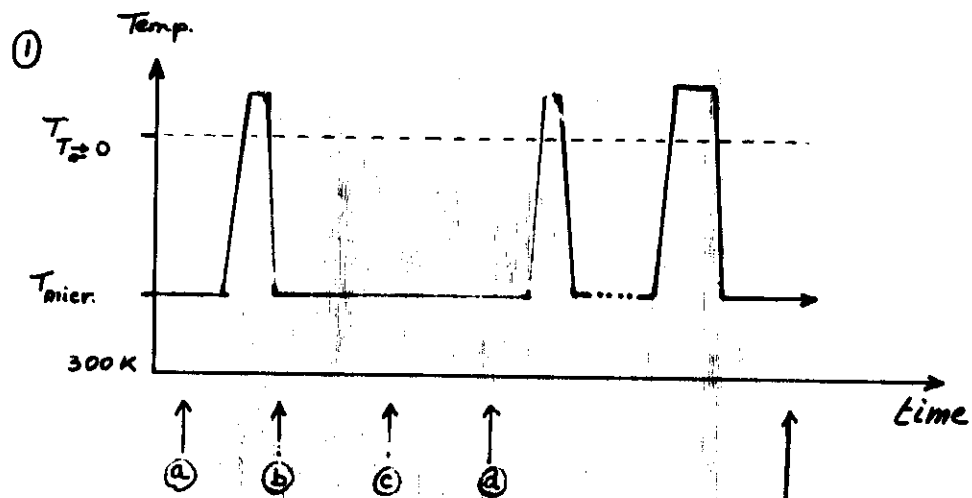
Diffuse Interfaces

1. HREM: NO tetragonal region
2. Diffraction: orthorhomb. smaller than in O_7
3. Monte Carlo: vacancies at the interface
4. HREM simulations: curved interfaces

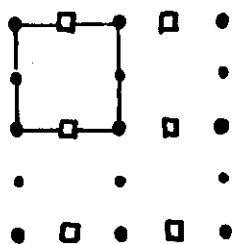
TWINS, NOT EXACTLY IN (110), WITH LOCAL OXYGEN DEFICIENCY



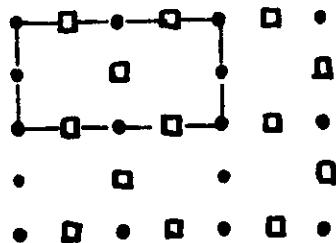
IN SITU EXPERIMENT



H. Van der
W.M.M. Broekink
"Philips" Bindhouwer

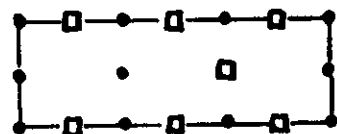


$x = 7$

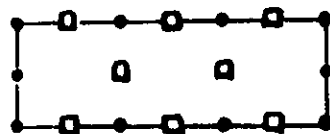


$x = 6.5$

$2a_o$
 O_{II}

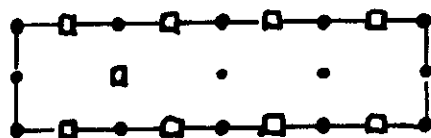


$x = 6.67$

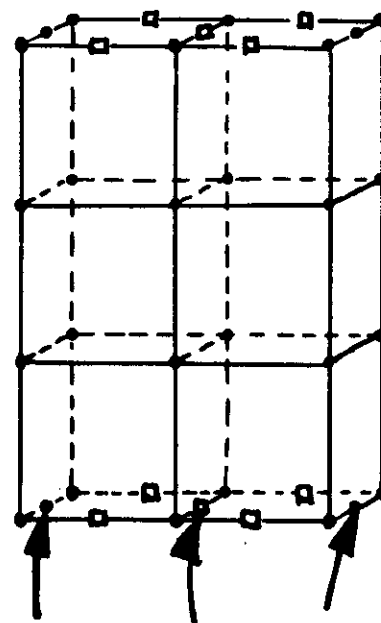


$x = 6.33$

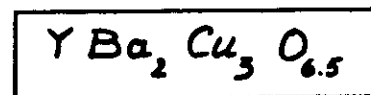
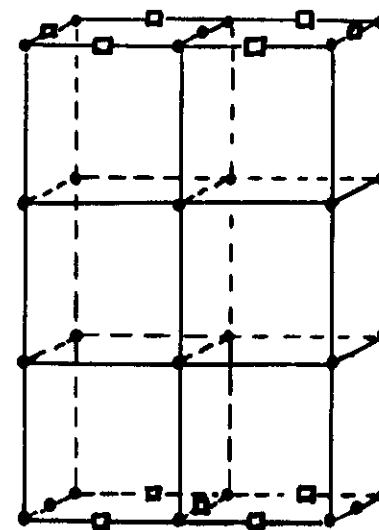
$9a_o$



$x = 6.75$



1.17 nm



The $2\sqrt{2} \times 2\sqrt{2}$ structure

Composition: $O_{6.25}-O_{6.0}$

Symmetry: $P4b2$ (90)
or $P42_12$ (117)

STRUCTURE:

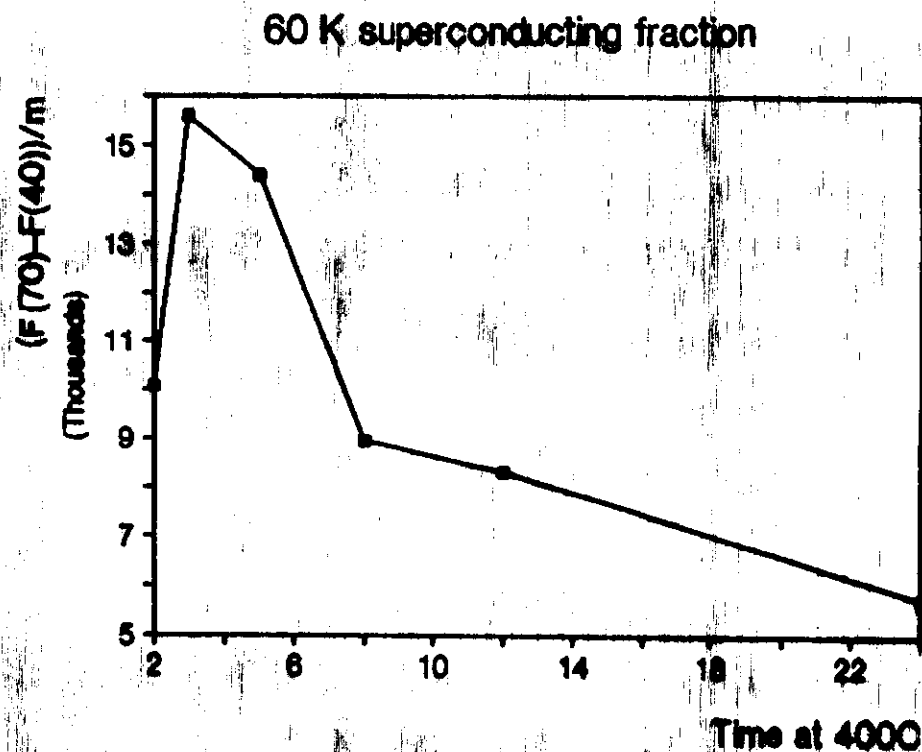
a) oxygen ordering

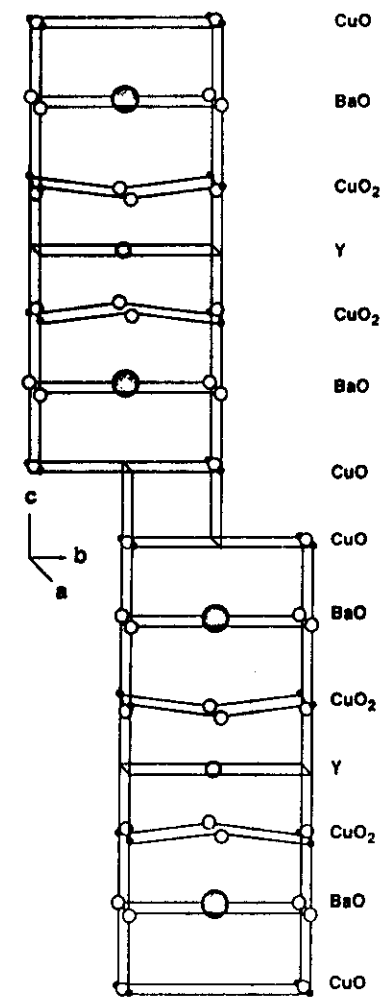
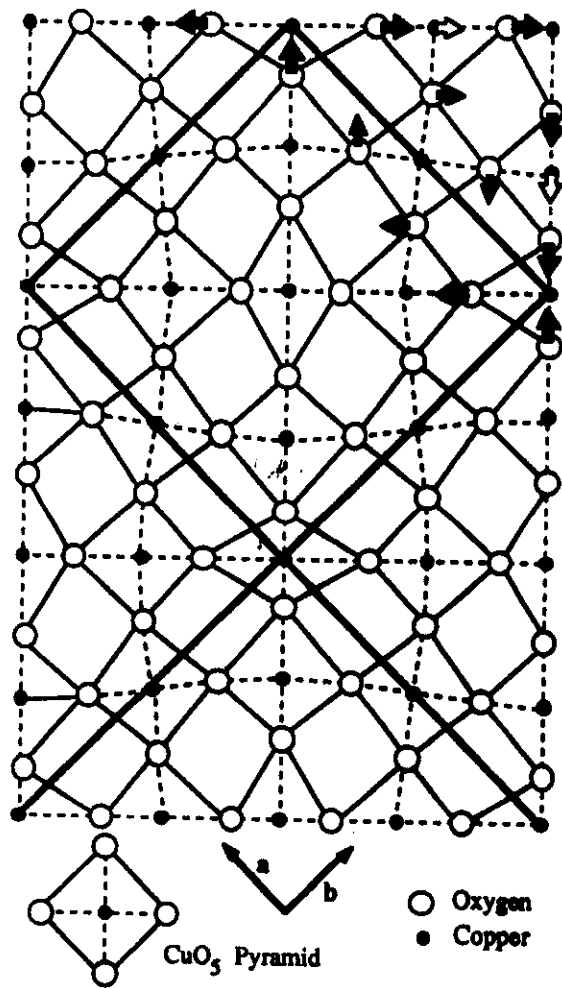
- 1) In the CuO_{1-x} plane $\rightarrow O_{6.5}$
- 2) + In the BaO plane $\rightarrow O_{6.25}$

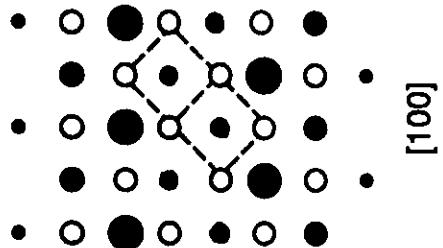
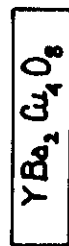
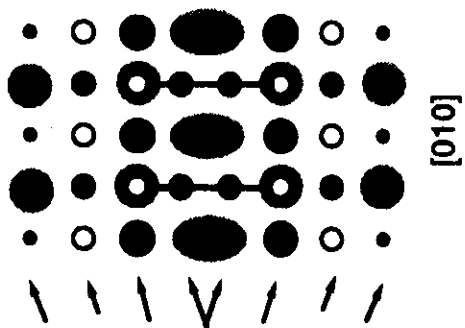
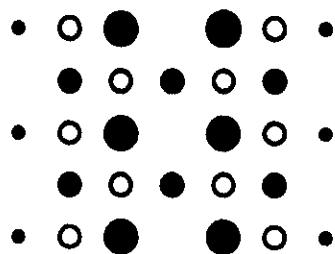
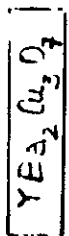
BUT : E.D. INTENSITIES DO NOT FIT

b) distortions (Jahn-Teller) in the CuO_2 plane

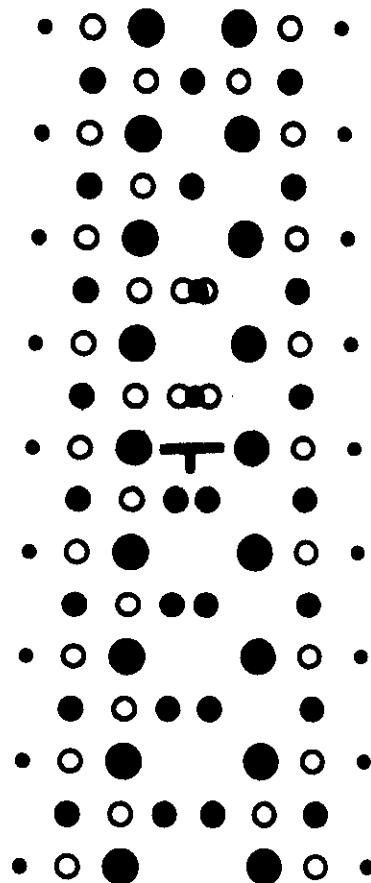
- $\rightarrow$ Composition OK
- $\rightarrow$ Symmetry OK
- $\rightarrow$ E.D. intensities OK

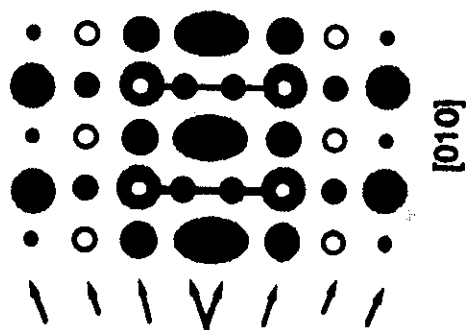
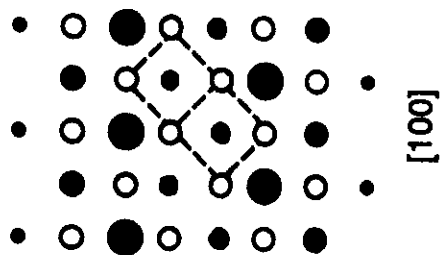
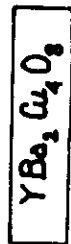




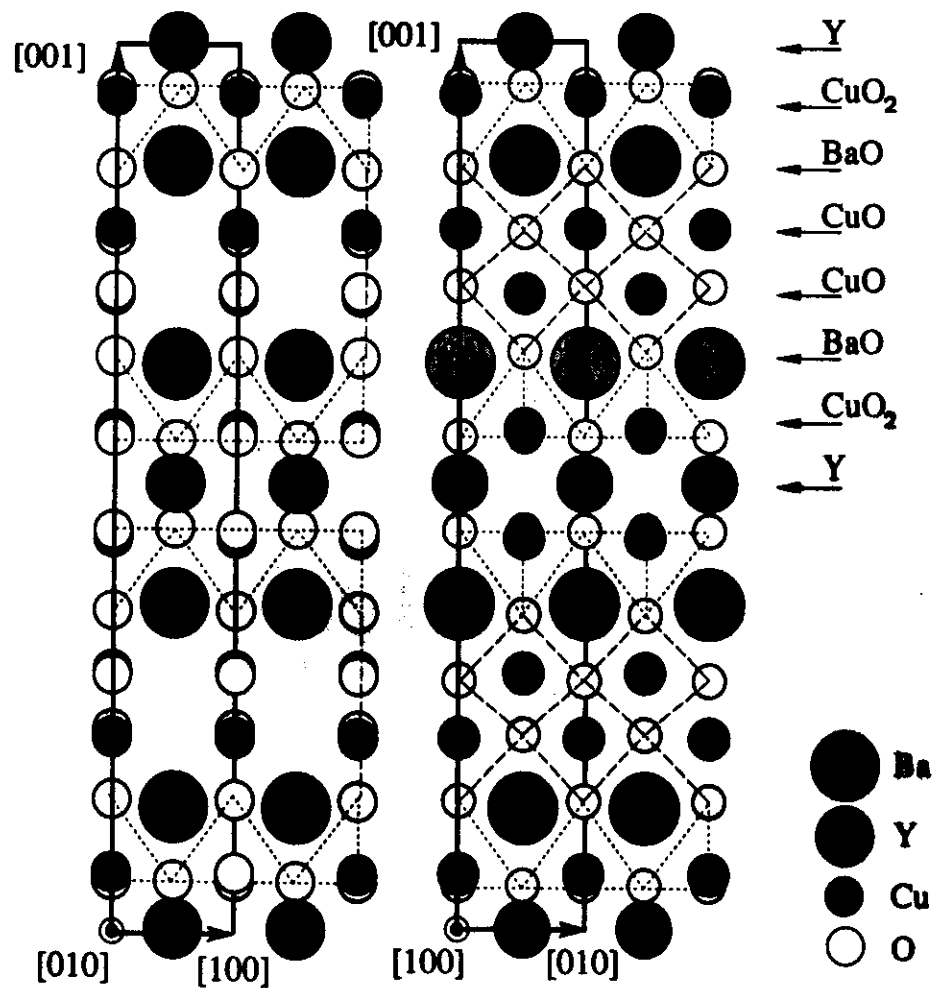
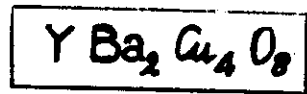
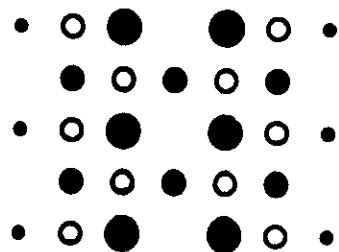
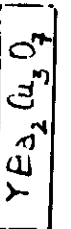


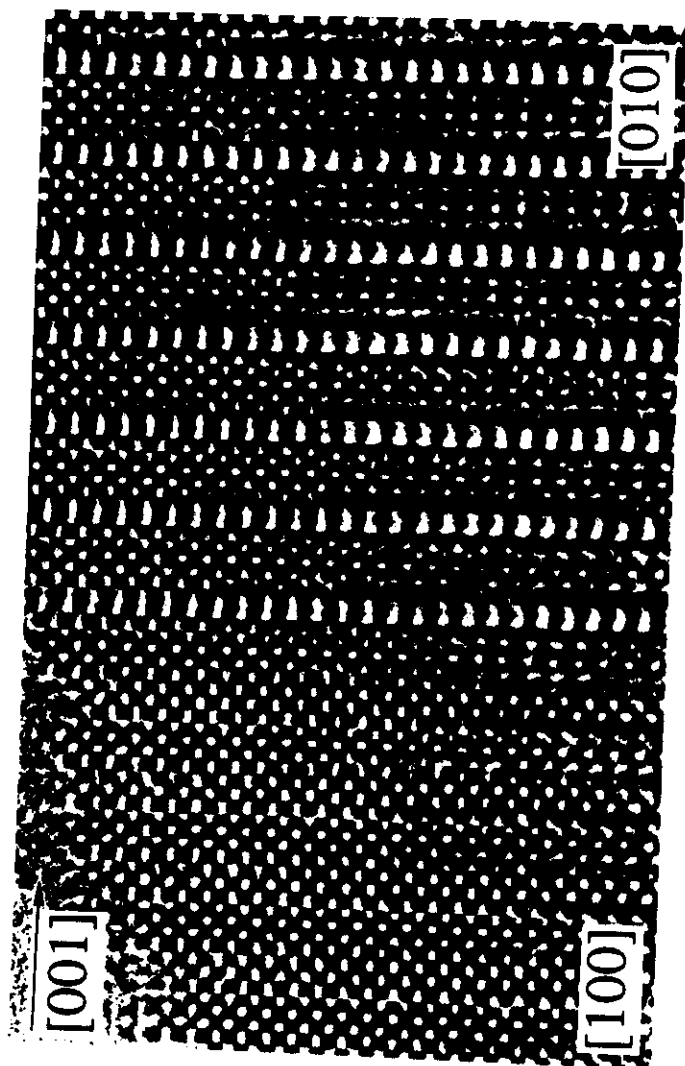
Prismatic Dislocation $\vec{b} = \frac{1}{6}c[001]$





Y CuO₂ BaO CuO BaO CuO₂ Y





MODULATED STRUCTURE

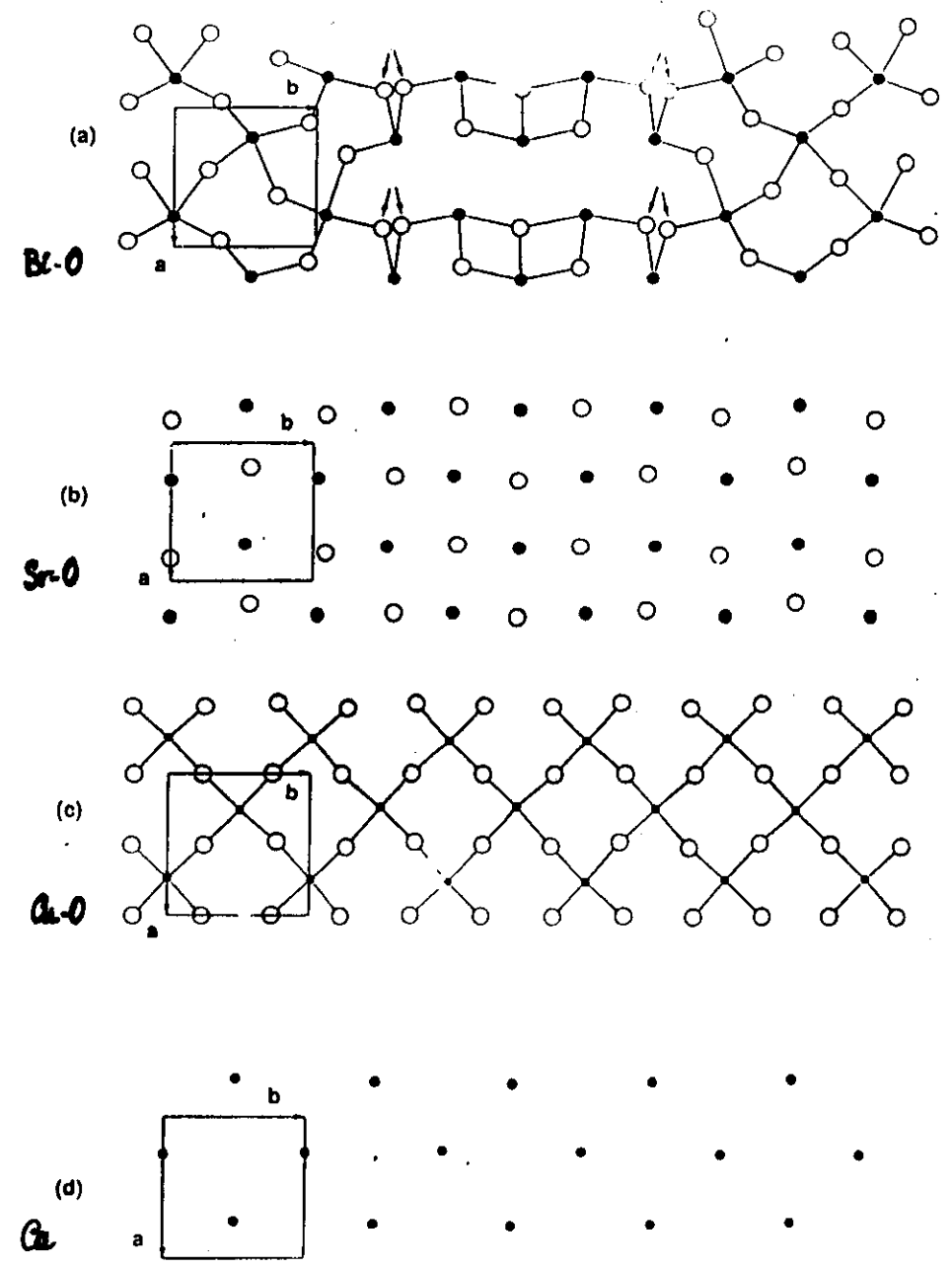
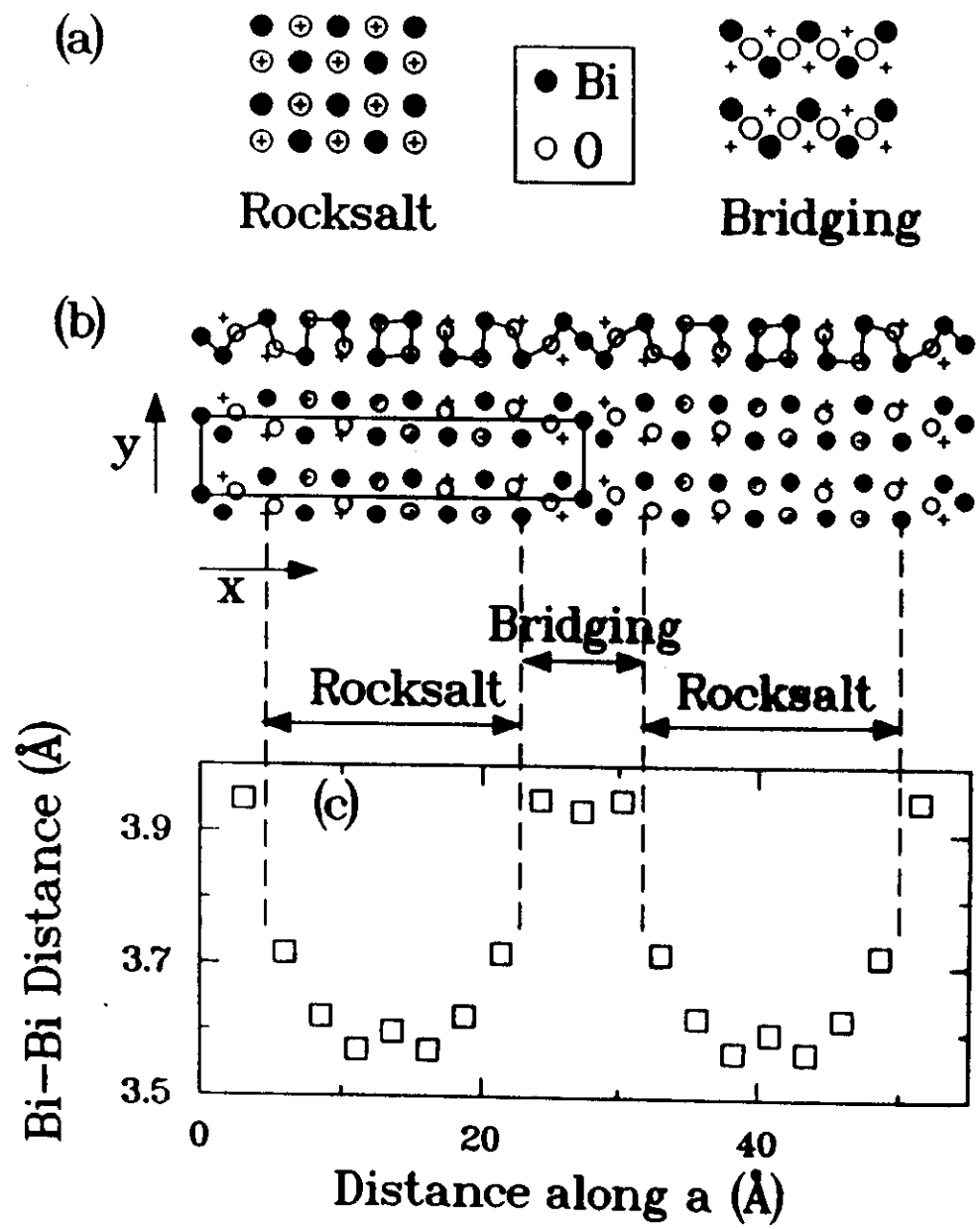
MODELS ??

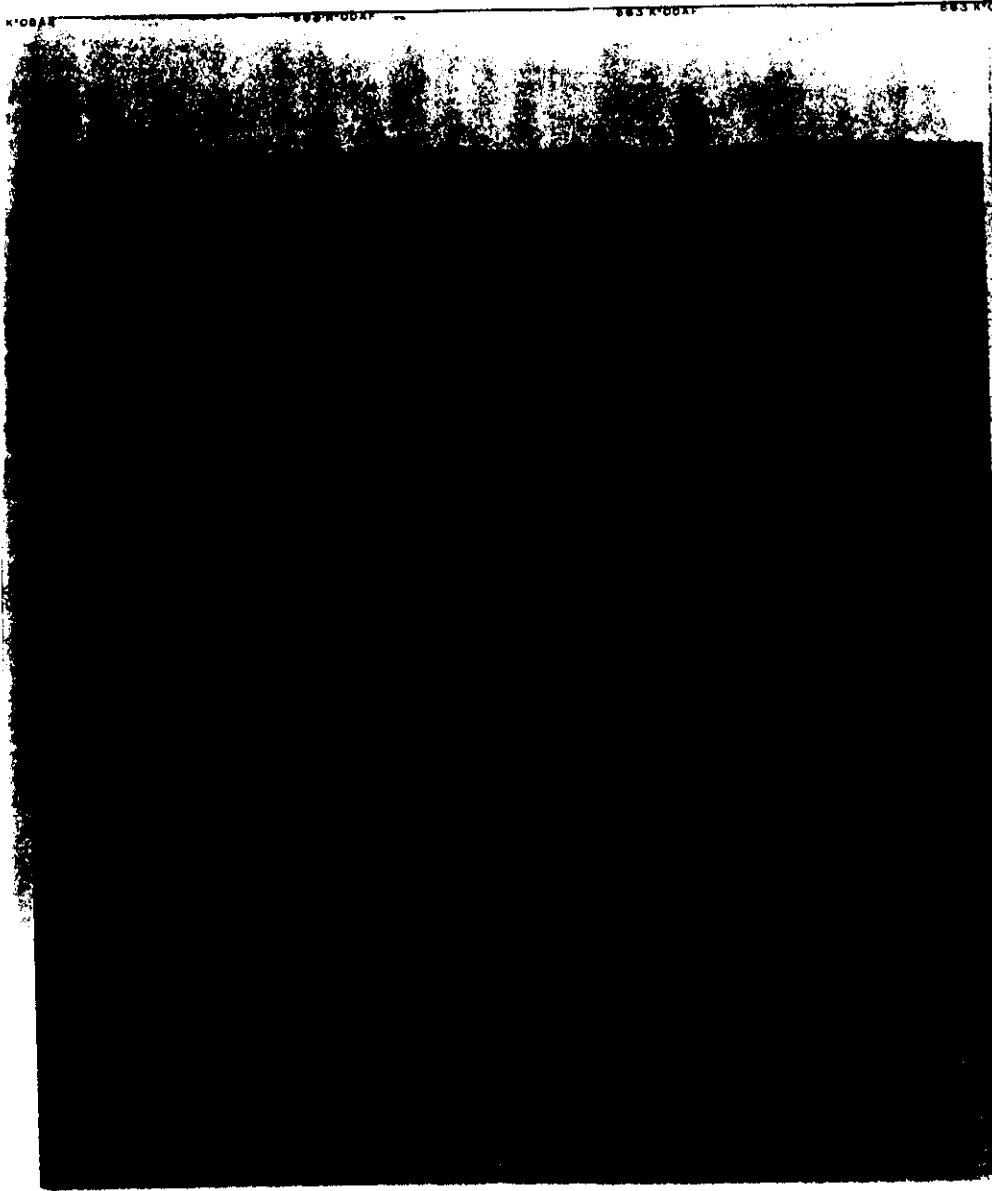
- EXTRA OXYGEN
- $\text{Sr} \leftrightarrow \square$
- $\text{Bi} \rightarrow \text{Cu}$
- $\text{Sr} \rightarrow \text{Bi}$
-

EM DATA

- NO TEMP DEPENDENCE
- $I(hklm)$ with $m \uparrow$
- $\text{Sr}_2 \rightarrow \text{Sr}_{2-x}\text{La}_x (\text{Bi}_x)$
- MAX. MOD. in BiO-PLAN.
- e^- IRRAD. $\rightarrow$ MOD. CHAN

EXTRA OXYGEN $\rightarrow$ Bi-COORDIN.
CHANGE





(ZBC 885-5534)

$\text{Bi}_2\text{Sr}_2\text{Ca}_n\text{Cu}_{1+n}\text{O}_{6+2n}$	Short notation	c/2 (nm)	Tc (K)
2 2 0 1 (n=0)	A	1.2	20
2 2 1 2 (n=1)	B	1.53	30
2 2 2 3 (n=2)	C	1.9	110
2 2 3 4 (n=3)	D	2.2	135 ?

REAL SPACE MODULATION

- a) reconstruct 3D reciprocal space of the modulated structure
- b) deduce the complete Bravais symbol of the 4D structure
- c) derive the modulation function (for each atom type) from superspace symmetry
(see De Wolff Acta Cryst 1977 and De Wolff et al. Acta Cryst 1981)

Application to $\text{Bi}_2\text{Sr}_2\text{Ca}_2\text{Cu}_3\text{O}_{10}$
and $\text{Tl}_2\text{Ba}_2\text{CuO}_6$

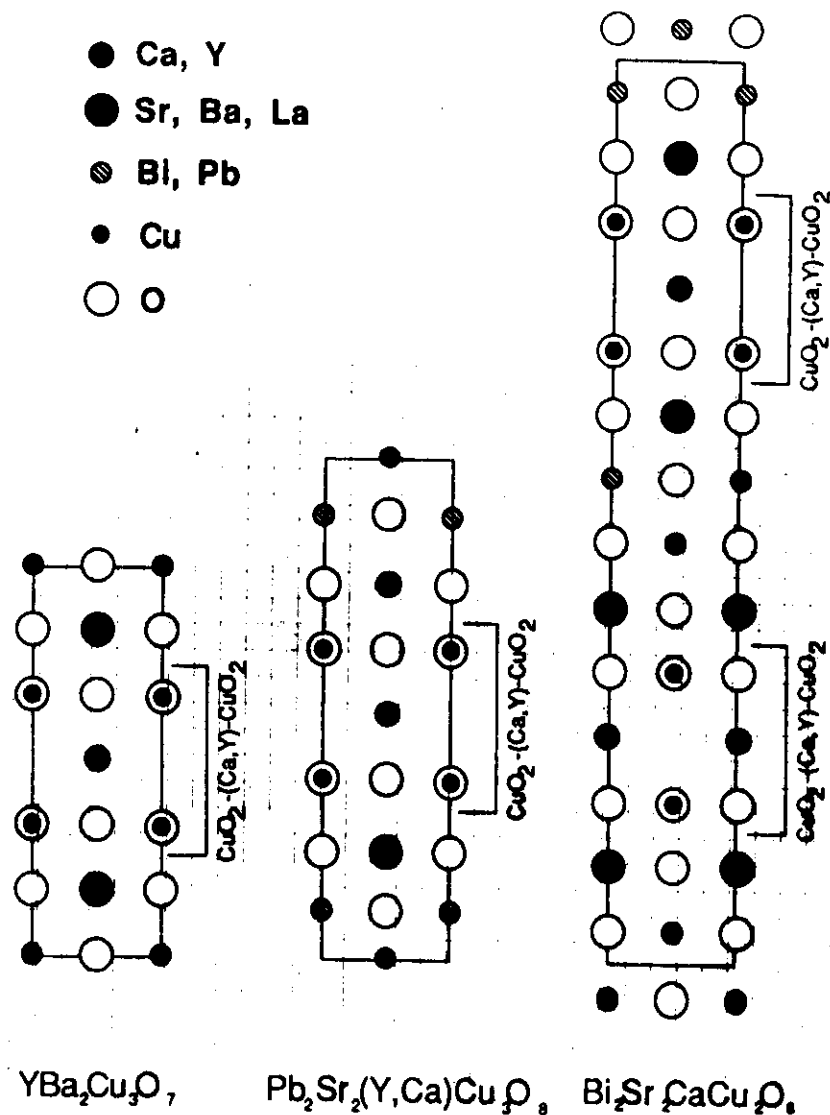


fig 1

ELECTRON MICROSCOPY FOR MATERIALS SCIENCE

Instruments	Purch.	Acc. Voltage	Resolving Power	Applications
JEOL JEM 1250	1973	1250 kV	4 Å	MICROELECTRONIC COMP. IRRADIATION SIMULATION PHASE TRANSITIONS
JEOL JEM 4000 EX	1983	400 kV	1.7 Å	HIGH RESOLUTION E.M. STRUCTURE DETERMINATION DEFECT CHARACTERIZATION
JEOL JEM 200 CX	1980	200 kV	2.5 Å	STEM X-RAY MICROANALYSIS SIDE ENTRY CONFIGURATION
JEOL JEM 100 C	1972	100 kV	5 Å	PHASE TRANSFORM. STUDIES ELECTRON DIFFRACTION
PHILIPS EM 300	1967	100 kV	10 Å	SCANNING EL. MIC. SURFACE STUDIES
JEOL NM T200A	1987	40 kV		

Y-Ba-Cu-O

A. $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$

- structure des macles (110)
- défauts (001)
- l'influence de l'oxygène
 $\text{O} \rightarrow 2a_0 \rightarrow (na_0) \rightarrow 2\sqrt{2} \times 2\sqrt{2} \rightarrow \text{cubic}$
- le plateau 60 K à $\text{O}_{6.5}-\text{O}_{6.6}$ (K.U. Leuven)
 (Argonne Nat. Lab.)
- la structure $2\sqrt{2} \times 2\sqrt{2}$
- les irradiations aux ions lourds (Orsay)
- substitutions de Cu par Fe (ULB Bruxelles)

B. $\text{YBa}_2\text{Cu}_4\text{O}_8$

(Phillips Eindhoven)